

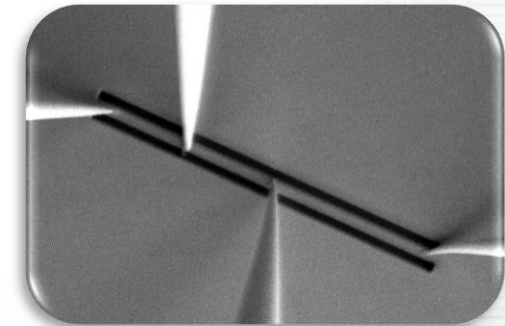
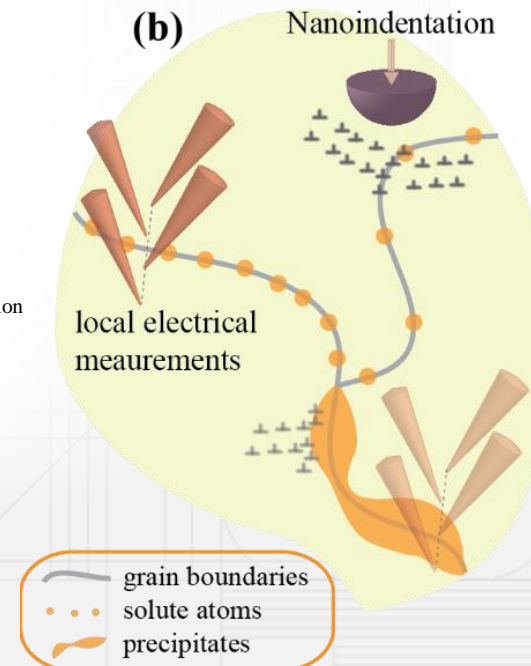
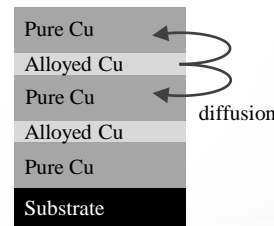
Open PhD. Position

Grain growth and electrical properties of multilayer Cu-Mn thin films: Segregation vs. Precipitation

The project unravels microstructure evolution of multi-layer metallic thin films, and its impact on the electrical resistivity. With a focus on segregation vs. precipitation effects/

The project includes:

- Multilayer sputtering of metal thin films
- Advanced structural and chemical characterization
- In-situ SEM electrical characterization



in-situ SEM
4-point-probe measurement

Project in collaboration with a
Max-Planck Institute